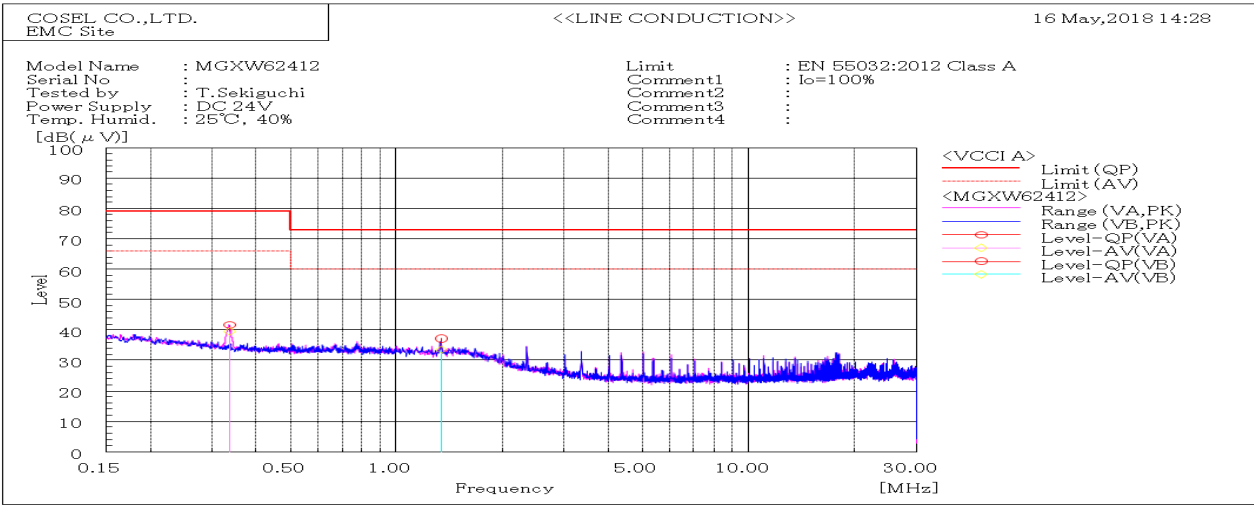
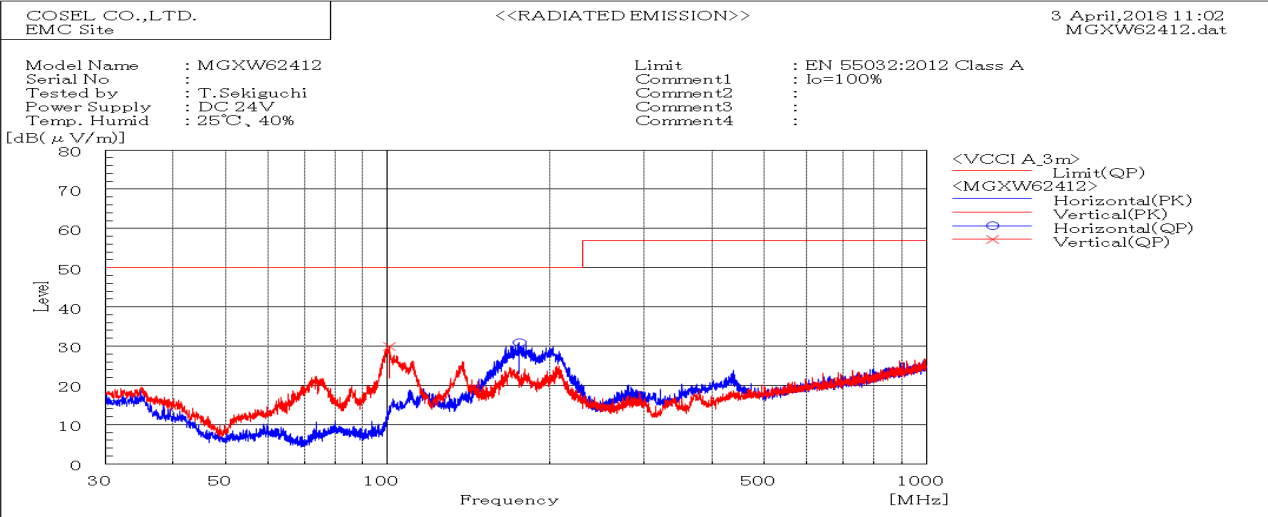


DATA SHEET		Date	18-Apr-18
Model	MGXW62412	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Sekiguchi



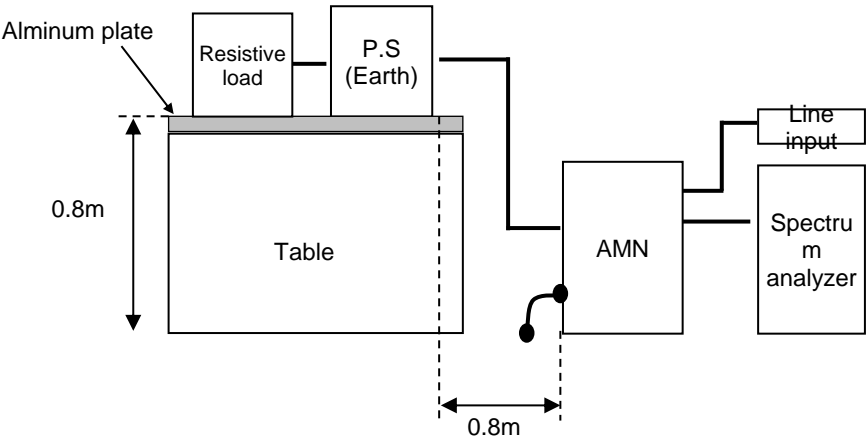
Frequency MHz	Line Phase	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
1.34425	VB	37.2	33.5	73	60	35.8	26.5	Pass	
0.33729	VA	41.8	39.4	79	66	37.2	26.6	Pass	



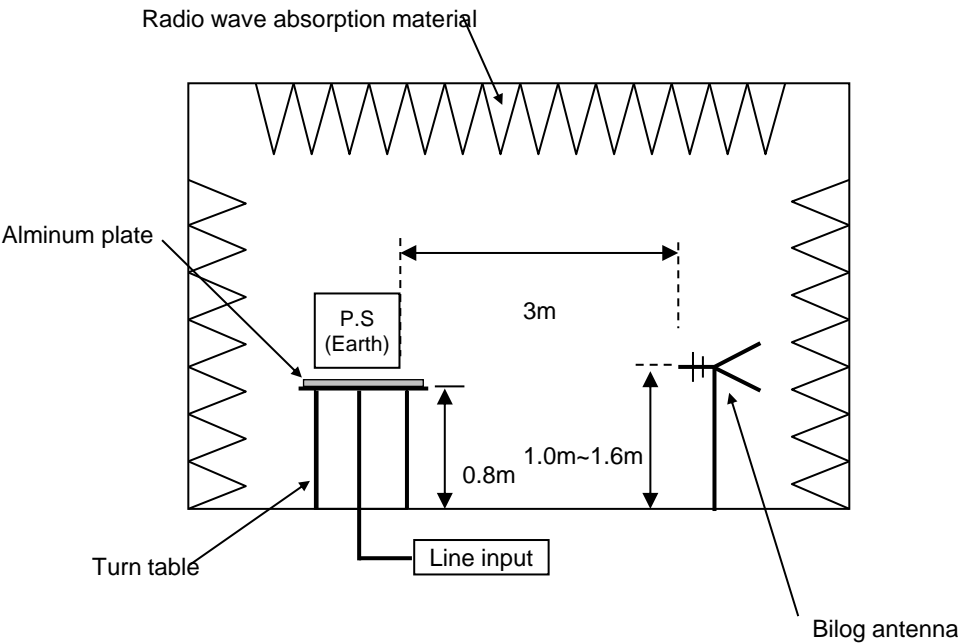
Frequency MHz	Polarization	Stability	Level dB(μV)	Limit dB(μV/m)	Margin dB(μV/m)	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
101.595	V	Stable	24.9	50.0	25.1	Pass	127	333	
175.272	H	Stable	25.7	50.0	24.3	Pass	150	339	

DATA SHEET		Date	18-Apr-18
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Sekiguchi

1. Line conduction



2. Radiated emission

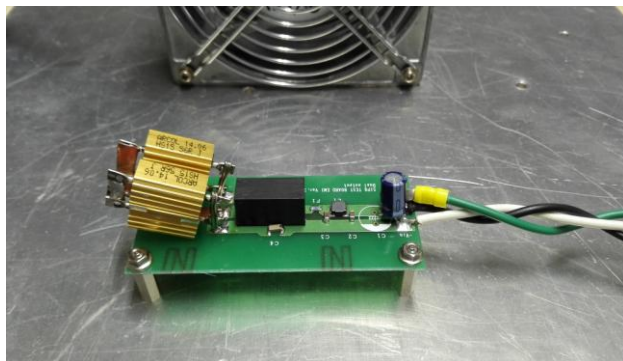


## Conditions

Test : EMI  
Model Name : MGXW6□□

○Photographs of Test Set-Up

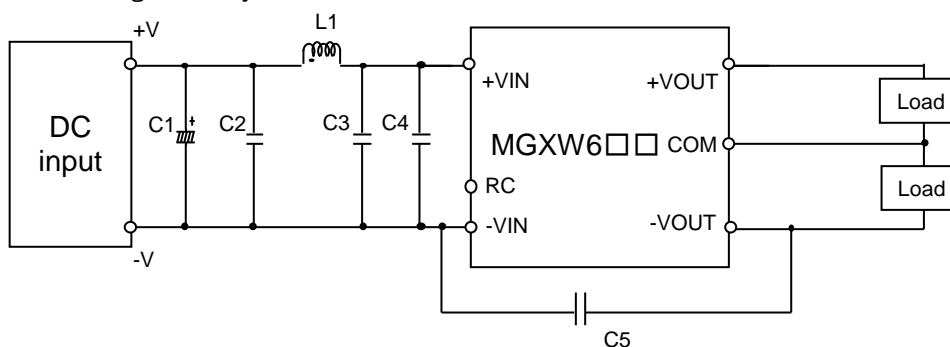
### LINE CONDUCTION



### RADIATED EMISSION



○Testing circuitry



- C1 : MGXW624□□ 100V 39 $\mu$  F Electric capacitor (LXVseries NIPPON CHEMI-CON)
- C2 : MGXW624□□ 100V 2.2 $\mu$  F Ceramic capacitor (GRM31CC72A225K MURATA MANUFACTURING)
- C3 : MGXW624□□ 100V 2.2 $\mu$  F Ceramic capacitor (GRM31CC72A225K MURATA MANUFACTURING)
- C4 : MGXW624□□ 100V 2.2 $\mu$  F Ceramic capacitor (GRM31CC72A225K MURATA MANUFACTURING)
- C5 : MGXW624□□ 2kV 2200pF Ceramic capacitor (GR443QR73D222K MURATA MANUFACTURING)
- L1 : MGXW624□□ 1050mA 22 $\mu$  H Inductor (LQH5BPN220MT0 MURATA MANUFACTURING)